

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Gary A. Frazier
Serial No.: Unknown
Filing Date: November 19, 2003
Title: METHOD AND APPARATUS FOR
GENERATING A PULSE OF
VERY NARROW WIDTH

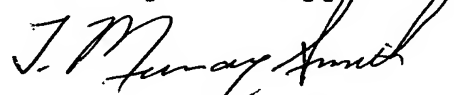
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

INFORMATION DISCLOSURE STATEMENT

Pursuant to the provisions of 37 CFR §§ 1.56, 1.97 and 1.98, Applicant is enclosing several documents which may be material to examination of the present application. The enclosed documents are listed on enclosed Form PTO-1449. Favorable consideration of the present application is respectfully requested.

Respectfully submitted,
BAKER BOTTS L.L.P.
Attorneys for Applicant



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Date: November 19, 2003

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Enclosures: Form PTO-1449, and one copy
of each listed document

PTO-1449 Information Disclosure Citation In an Application	Application No. Unknown		Applicant(s) Gary A. Frazier	
	Docket Number 004578.1373	Group Art Unit Unknown	Filing Date November 19, 2003	

U.S. PATENT DOCUMENTS

		DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
	A	6,348,887	02/19/02	Broekaert			
	B	6,509,859	01/21/03	van der Wagt			
	C						
	D						
	E						
	F						
	G						
	H						
	I						
	J						
	K						
	L						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	M							
	N							

DOCUMENT (Including Author, Title, Source, Pertinent Pages, and Date)

	O	Richard H. Mathews, et al., "A New RTD-FET Logic Family", Proceedings of the IEEE, Vol. 87, No. 4, April 1999, pp. 596-605.
	P	Product Data Sheet, "Sampling Phase Detector", Metelics Corporation, Sunnyvale, California, 6 unnumbered pages, published prior to 2000.
	Q	Product Data Sheet, "Sampling Phase Detectors" Alpha Industries, Inc., Woburn, Massachusetts, 3 pages, published prior to 2000.
	R	"Sketch A (Prior Art)", 1 sheet, author and source unknown.
	S	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

U.S. PATENT AND TRADEMARK OFFICE